

Jupiter-XR AFM: High Resolution, High Stability, and High Speed

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Abstract

The **Jupiter XR** Atomic Force Microscope is the first and only large-sample AFM to offer both high-speed imaging and 100 μm image range in the standard instrument configuration. Jupiter XR enables higher resolution than any other large-sample AFM at scan rates 5-20x faster than most other AFMs. Jupiter XR provides complete 200mm sample access, faster results, a simpler user experience, and the versatility to excel in both academic research and industrial settings. In this virtual workshop, Asylum Research will demonstrate Jupiter's atomic resolution imaging capability, high-speed imaging as well as blueDrive photothermal excitation. Join us and find out why more customers are choosing Jupiter as their AFM solution.